IFW



P/1071-1593 CIP

In re Patent Application of:

Gaku KAMITANI

Date

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

: August 31, 2004

Serial No.

10/601,718

Group Art Unit

: 2863

Filed

June 23, 2003

Examiner

: Michael P. Nghiem

Confirmation No. :

8700

For

METHOD FOR CORRECTING MEASUREMENT ERROR,

METHOD OF DETERMINING QUALITY OF ELECTRONIC

COMPONENT AND DEVICE FOR MEASURING CHARACTERISTIC OF ELECTRONIC COMPONENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

RESPONSE TO NON-COMPLIANT AMENDMENT

Sir:

Applicant responds herein to the Notice of Non-Compliant Amendment mailed August 19, 2004.

Enclosed please find a re-executed copy of the "replacement" drawings mailed on July 28, 2004 stating "replacement" within the margins of each drawing (Figures 1-9) in accordance with the instructions contained on page 3 in paragraph 1 of said Notice. The amendment is now believed to be in compliance with all the appropriate statutory and regulatory requirements.

Reconsideration of the application is respectfully requested.

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on August 31, 2004:

James A. Finder

Name of applicant, assignee or Registered Representative

August 31, 2004

Date of Signature

JAF:msd

Respectfully submitted

James A. Finder

Registration No.: 30,173

OSTROLENK, FABER, GERB & SOFFEN, LLP

1180 Avenue of the Americas

New York, New York 10036-8403

Telephone: (212) 382-0700